

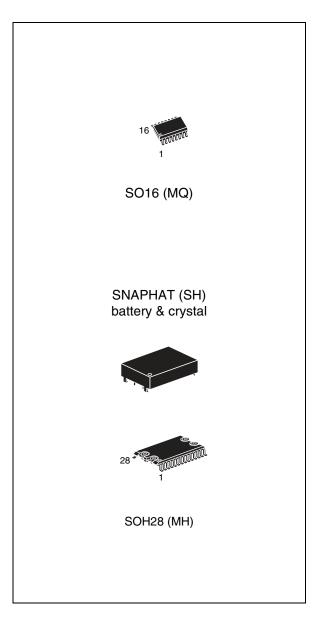
M41T315Y M41T315V, M41T315W

Serial access phantom RTC supervisor

Not For New Design

Features

- 3.0V, 3.3V, or 5V operating voltage
- Real-time clock keeps track of tenths/hundredths of seconds, seconds, minutes, hours, days, date of the month, months, and years
- Automatic leap year correction valid up to 2100
- Automatic switch-over and deselect circuitry
- Choice of power-fail deselect voltages: (V_{PFD} = power-fail deselect voltage)
 - M41T315Y^(a): $V_{CC} = 4.5$ to 5.5V 4.25V $\leq V_{PFD} \leq 4.50V$
 - M41T315V: $V_{CC} = 3.0 \text{ to } 3.6V$ $2.80V \le V_{PFD} \le 2.97V$
 - M41T315W: $V_{CC} = 2.7 \text{ to } 3.3V$ $2.60V \le V_{PFD} \le 2.70V$
- No address space required to communicate with RTC
- Provides nonvolatile supervisor functions for battery backup of SRAM
- Full ±10% V_{CC} operating range
- Industrial operating temperature range (-40 to +85°C)
- Ultra-low battery supply current of 500nA (max)
- Optional packaging includes A 28-lead SOIC and SNAPHAT[®] top (to be ordered separately)
- SNAPHAT package provides direct connection for a snaphat top, which contains the battery and crystal
- RoHS compliant
 - Lead-free second level interconnect



a. Contact local ST sales office for availability.

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1 Description

The M41T315Y/V/W RTC Supervisor is a combination of a CMOS TIMEKEEPER[®] and a nonvolatile memory supervisor. Power is constantly monitored by the memory supervisor. In the event of power instability or absence, an external battery maintains the timekeeping operation and provides power for a CMOS static RAM by switching on and invoking write protection to prevent data corruption in the memory and RTC.

The clock keeps track of tenths/hundredths of seconds, seconds, minutes, hours, day, date, month, and year information. The last day of the month is automatically adjusted for months with less than 31 days, including leap year correction.

The clock operates in one of two formats:

a 12-hour mode with an AM/PM indicator;

or

a 24-hour mode

The nonvolatile supervisor supplies all the necessary support circuitry to convert a CMOS RAM to a nonvolatile memory. The M41T315Y/V/W can be interfaced with RAM without leaving gaps in memory.

The M41T315Y/V/W is supplied in a 28-lead SOIC SNAPHAT® package (which integrates both crystal and battery in a single SNAPHAT top) or a-16 pin SOIC. The 28-pin, 330mil SOIC provides sockets with gold plated contacts at both ends for direct connection to a separate SNAPHAT housing containing the battery and crystal. The unique design allows the SNAPHAT battery/crystal package to be mounted on top of the SOIC package after the completion of the surface mount process.

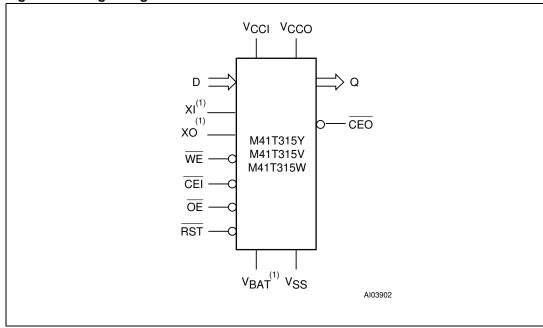
Insertion of the SNAPHAT housing after reflow prevents potential battery and crystal damage due to the high temperatures required for device surface-mounting. The SNAPHAT housing is also keyed to prevent reverse insertion.

The 28-pin SOIC and battery/crystal packages are shipped separately in plastic anti-static tubes or in Tape & Reel form. For the 28-lead SOIC, the battery/crystal package (e.g., SNAPHAT) part number is "M4TXX-BR12SH" (see *Table 17 on page 28*).

Caution:

Do not place the SNAPHAT battery/crystal top in conductive foam, as this will drain the lithium button-cell battery.

Figure 1. Logic diagram



1. For 16-pin SOIC only

Table 1. Signal names

9	
XI-XO	32.768 KHz crystal connection
D	Data input
Q	Data output
RST	Reset input
CEO	Chip enable output
CEI	Chip enable input
V _{BAT}	Battery input
ŌĒ	Output enable input
WE	WRITE enable input
V _{CCO}	Switched supply voltage output
V _{CCI}	Supply voltage input
V _{SS}	Ground
NC	Not connected internally
DU	Don't Use

Figure 2. 16-pin SOIC connections

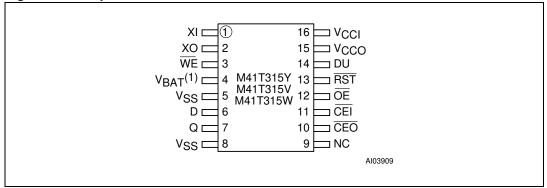


Figure 3. 28-pin SOIC connections

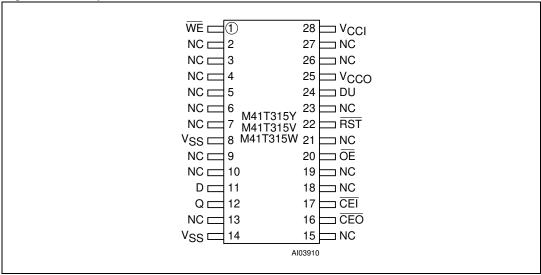
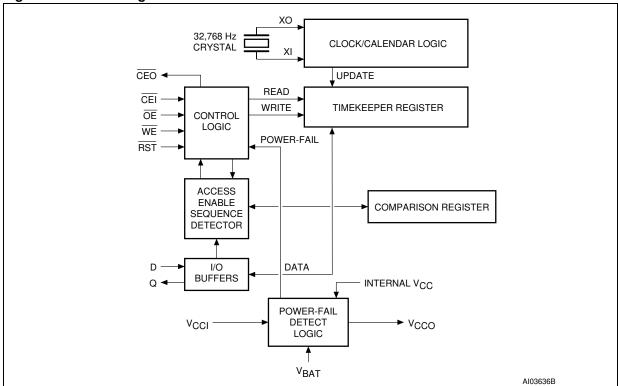


Figure 4. Block diagram



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D0-D7 A0-An DATA I/O A0-An CMOS SRAM WE WE ŌE · ŌĒ CE VCC v_{CCO} CEO ŌE WE V_{CC} M41T315Y/V/W CEI CE · Q RST -RST v_{CCI} V_{BAT} BAT - V_{SS} 32.768 Hz CRYSTAL ۷ss

M41T315Y/V/W to RAM/clock interface Figure 5.

2 Operation

Figure 6 on page 11 illustrates the main elements of the device. The following paragraphs describe the signals and functions.

Communication with the clock is established by pattern recognition of a serial bit stream of 64 bits which must be matched by executing 64 consecutive WRITE cycles containing the proper data on data in (D). All accesses which occur prior to recognition of the 64-bit pattern are directed to memory via the chip enable output pin ($\overline{\text{CEO}}$).

After recognition is established, the next 64 READ or WRITE Cycles either extract or update data in the clock and $\overline{\text{CEO}}$ remains high during this time, disabling the connected memory (see *Table 2 on page 11*).

Data transfer to and from the timekeeping function is accomplished with a serial bit stream under control of chip enable input (CEI), output enable (OE), and WRITE enable (WE). Initially, a READ cycle using the CEI and OE control of the clock starts the pattern recognition sequence by moving the pointer to the first bit of the 64-bit comparison register. Next, 64 consecutive WRITE cycles are executed using the CEI and WE control of the clock. These 64 WRITE cycles are used only to gain access to the clock.

When the first WRITE cycle is executed, it is compared to the first bit of the 64-bit comparison register. If a match is found, the pointer increments to the next location of the comparison register and awaits the next WRITE cycle.

If a match is not found, the pointer does not advance and all subsequent WRITE cycles are ignored. If a READ cycle occurs at any time during pattern recognition, the present sequence is aborted and the comparison register pointer is reset. Pattern recognition continues for a total of 64 WRITE cycles as described above until all the bits in the comparison register have been matched (see *Figure 8 on page 14*).

With a correct match for 64 bits, access to the registers is enabled and data transfer to or from the timekeeping registers may proceed. The next 64 cycles will cause the device to either receive data on D, or transmit data on Q, depending on the level of \overline{OE} pin or the WE pin. Cycles to other locations outside the memory block can be interleaved with \overline{CEI} cycles without interrupting the pattern recognition sequence or data transfer sequence to the device.

For a SO16 pin package, a standard 32.768 kHz quartz crystal can be directly connected to the M41T315Y/V/W via pins 1 and 2 (XI, XO). The crystal selected for use should have a specified load capacitance ($C_{\rm I}$) of 12.5 pF (see *Table 10 on page 21*).

	o poraumg modeo						
Mode	V _{cc}	CEI	ŌĒ	WE	D	Q	Power
Deselect	4.5 to 5.5V	V _{IH}	Х	Х	Hi-Z	Hi-Z	Standby
WRITE	or 3.0 to 3.6V or 2.7 to 3.3V	V _{IL}	Х	V _{IL}	D _{IN}	Hi-Z	Active
READ		V _{IL}	V _{IL}	V _{IH}	Hi-Z	D _{OUT}	Active
READ		V _{IL}	V _{IH}	V _{IH}	Hi-Z	Hi-Z	Active
Deselect	V _{SO} to V _{PFD} (min) ⁽¹⁾	Х	Х	Х	Hi-Z	Hi-Z	CMOS standby
Deselect	≤ V _{SO} ⁽¹⁾	Х	Х	Х	Hi-Z	Hi-Z	Battery back-up mode

Table 2. Operating modes

2.1 Non-volatile supervisor operation

A switch is provided to direct power from the battery input or V_{CCI} to V_{CCO} with a maximum voltage drop of 0.3 Volts. The V_{CCO} output pin is used to supply uninterrupted power to CMOS SRAM. The M41T315Y/V/W safeguards the clock and RAM data by power-fail detection and write protection.

Power-fail detection occurs when V_{CCI} falls below V_{PFD} which is set by an internal bandgap reference. The M41T315Y/V/W constantly monitors the V_{CCI} supply pin. When V_{CCI} is less than V_{PFD} , power-fail circuitry forces the chip enable output (\overline{CEO}) to V_{CCI} or V_{BAT} 0.2 volts for external RAM write protection. During nominal supply conditions, \overline{CEO} will track \overline{CEI} with a propagation delay. Internally, the M41T315Y/V/W aborts any data transfer in progress without changing any of the device registers and prevents future access until V_{CCI} exceeds V_{PFD} . Figure 5 on page 9 illustrates a typical RAM/clock interface.

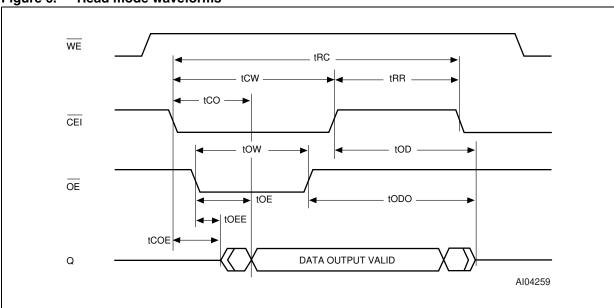


Figure 6. Read mode waveforms

^{1.} See Table 11 on page 21 for details.

Figure 7. Write mode waveforms

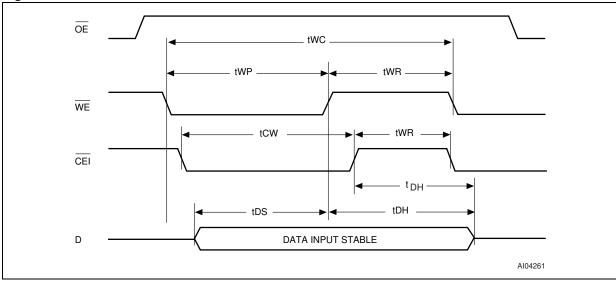


Table 3. AC electrical characteristics (M41T315Y)

Symbol		Parameter ⁽¹⁾	Min	Тур	Max	Units
t _{AVAV}	t _{RC}	READ cycle time	65			ns
t _{ELQV}	t _{CO}	CEI access time			55	ns
t _{GLQV}	t _{OE}	OE access time			55	ns
t _{ELQX}	t _{COE}	CEI to output low Z	5			ns
t _{GLQX}	t _{OEE}	OE to output low Z	5			ns
t _{EHQZ}	t _{OD}	CEI to output high Z			25	ns
t _{GHQZ}	t _{ODO}	OE to output high Z			25	ns
	t _{RR}	READ recovery	10			ns
t _{ELEH}	t _{CW}	CEI pulse width	55			ns
t _{GLGH}	t _{OW}	OE pulse width	55			ns
t _{AVAV}	t _{WC}	WRITE cycle	65			ns
t_{WLWH}	t _{WP}	WRITE pulse width	55			ns
t _{EHAX} t _{WHAX}	t _{WR} ⁽²⁾	WRITE recovery	10			ns
t _{DVEH} t _{DVWH}	t _{DS} (3)	Data setup	30			ns
t _{EHDX} t _{WHDX}	t _{DH} (3)	Data hold time	0			ns
	t _{RST}	RST pulse width	65			ns

^{1.} Valid for ambient operating temperature: TA = -40 to $85^{\circ}C$; VCC = 4.5 to 5.5V (except where noted).

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^{2.} t_{WR} is a function of the latter occurring edge of \overline{WE} or \overline{CEI} .

^{3.} t_{DH} and t_{DS} are functions of the first occurring edge of $\overline{\text{WE}}$ or $\overline{\text{CEI}}$ in RAM mode.

Table 4. AC electrical characteristics (M41T315V/W)

Symbol		Parameter ⁽¹⁾	Min	Тур	Max	Units
t _{AVAV}	t _{RC}	READ cycle time	85			ns
t _{ELQV}	t _{CO}	CEI access time			85	ns
t _{GLQV}	t _{OE}	OE access time			85	ns
t _{ELQX}	t _{COE}	CEI to output low Z	5			ns
t _{GLQX}	t _{OEE}	OE to output low Z	5			ns
t _{EHQZ}	t _{OD}	CEI to output high Z			30	ns
t _{GHQZ}	t _{ODO}	OE to output high Z			30	ns
	t _{RR}	READ recovery	20			ns
t _{ELEH}	t _{CW}	CEI pulse width	65			ns
t _{GLGH}	t _{OW}	OE pulse width	60			ns
t _{AVAV}	t _{WC}	WRITE cycle	85			ns
t _{WLWH}	t _{WP}	WRITE pulse width	60			ns
t _{EHAX}	t _{WR} ⁽²⁾	WRITE recovery	25			ns
t _{DVEH} t _{DVWH}	t _{DS} ⁽³⁾	Data setup	35			ns
t _{EHDX} t _{WHDX}	t _{DH} ⁽³⁾	Data hold time	5			ns
	t _{RST}	RST pulse width	85			ns

^{1.} Valid for ambient operating temperature: TA = -40 to $85^{\circ}C$; VCC = 4.5 to 5.5V (except where noted).

^{2.} t_{WR} is a function of the latter occurring edge of \overline{WE} or \overline{CEI} .

^{3.} t_{DH} and t_{DS} are functions of the first occurring edge of \overline{WE} or \overline{CEI} in RAM mode.

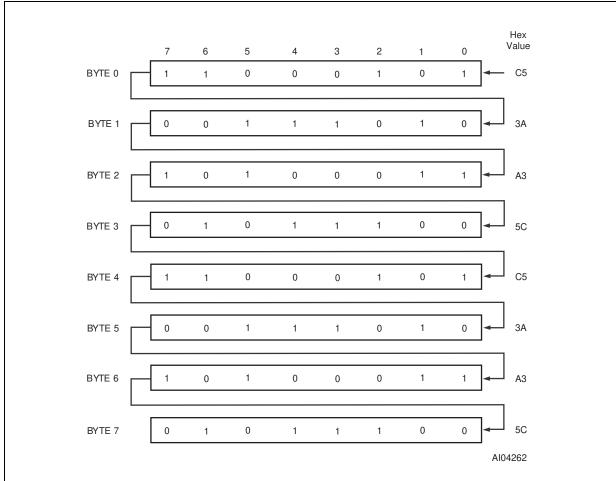


Figure 8. Comparison register definition

Note: Pattern recognition in "hex" is C5, 3A, A3, 5C, C5, 3A, A3, and 5C. The odds of this pattern being accidentally duplicated and sending aberrant entries to the RTC is less than 1 in 10¹⁹. This pattern is sent to the clock LSB to MSB.

2.2 Data retention

Most low power SRAMs on the market today can be used with the M41T315Y/V/W. There are, however some criteria which should be used in making the final choice of an SRAM to use. The SRAM must be designed in a way where the chip enable input disables all other inputs to the SRAM. This allows inputs to the M41T315Y/V/W and SRAMs to be Don't Care once V_{CCI} falls below V_{PFD} (min). The SRAM should also guarantee data retention down to V_{CC} = 2.0 volts. The chip enable access time must be sufficient to meet the system needs with the chip enable output propagation delays included. If the SRAM includes a second chip enable pin (E2), this pin should be tied to V_{OUT} .

If data retention lifetime is a critical parameter for the system, it is important to review the data retention current specifications for the particular SRAMs being evaluated. Most SRAMs specify a data retention current at 3.0 volts. Manufacturers generally specify a typical condition for room temperature along with a worst case condition (generally at elevated temperatures). The system level requirements will determine the choice of which value to

use. The data retention current value of the SRAMs can then be added to the IBAT value of the M41T315Y/V/W to determine the total current requirements for data retention. The available battery capacity for the SNAPHAT[®] of your choice can then be divided by this current to determine the amount of data retention available (see *Table 17 on page 28*).

For a further more detailed review of lifetime calculations, please see Application Note AN1012.

3 Clock operation

3.1 Clock register information

Clock information is contained in eight registers of 8 bits, each of which is sequentially accessed 1 bit at a time after the 64-bit pattern recognition sequence has been completed. When updating the clock registers, each must be handled in groups of 8 bits. Writing and reading individual bits within a register could produce erroneous results. These READ/WRITE registers are defined in *Table 5 on page 17*.

Data contained in the clock registers is in binary coded decimal format (BCD). Reading and writing the registers is always accomplished by stepping though all eight registers, starting with Bit 0 of Register 0 and ending with Bit 7 of Register 7.

3.2 AM-PM/12/24 mode

Bit 7 of the hours register is defined as the 12-hour or 24-hour mode select bit. When high, the 12-hour mode is selected. In the 12-hour mode, Bit 5 is the AM/PM bit with logic high being PM. In the 24-hour mode, Bit 5 is the second 10-hour bit (20-23 hours).

3.3 Oscillator and reset bits

Bits 4 and 5 of the day register are used to control the reset and oscillator functions. Bit 4 controls the reset pin input. When the Reset Bit is set to logic '1,' the reset input pin is ignored. When the Reset Bit is set to logic '0,' a low input on the reset pin will cause the device to abort data transfer without changing data in the timekeeping registers. Reset operates independently of all other inputs. Bit 5 controls the oscillator. When set to logic '0,' the oscillator turns on and the real-time clock/calendar begins to increment.

3.4 Zero bits

Registers 1, 2, 3, 4, 5, and 6 contain one (1) or more bits that will always read logic '0.' When writing to these locations, either a logic '1' or '0' is acceptable.

Table 5. RTC register map

									Function/range		
Register	D7	D6	D5	D4	D3	D2	D1	D0	BCD format		
0		0.1 se	conds			0.01 s	econds		seconds	00-99	
1	0	1	10 second	s		seconds			seconds	00-59	
2	0		10 minute:	3		min	utes		minutes	00-59	
3	12/24	0	10/ A/P	hrs	r	hours (24 hour format)			hours	01-12/ 00-23	
4	0	0	OSC	RST	0	da	y of the we	eek	day	01-07	
5	0	0	10 (date	date: day of the month			date	01-31		
6	0	0	0	10M	month			month	01-12		
7	7 10 years			year				year	00-99		

Keys:

A/P = AM/PM bit

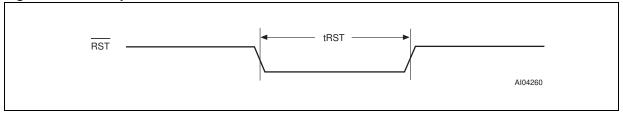
12/24 = 12 or 24-hour mode bit

OSC = Oscillator bit

 $\overline{\mathsf{RST}}$ = Reset bit

0 = Must be set to '0'

Figure 9. Reset pulse waveform



4 Maximum rating

Stressing the device above the rating listed in the "Absolute Maximum Ratings" table may cause permanent damage to the device. These are stress ratings only and operation of the device at these or any other conditions above those indicated in the Operating sections of this specification is not implied. Exposure to Absolute Maximum Rating conditions for extended periods may affect device reliability. Refer also to the STMicroelectronics SURE Program and other relevant quality documents.

Table 6. Ablolute maximum ratings

Symbol	Parameter	Value	Unit	
T _A	Operating temperature	−40 to +85	°C	
+	Storage temperature (V _{CC} , oscillator off) SNAPHAT® SOIC		-40 to +85	°C
T _{STG}			-55 to +125	°C
T _{SLD} ⁽¹⁾	Lead solder temperature for 10 seconds	260	°C	
V	M41T315		-0.3 to +7.0	V
V _{CCI}	Supply voltage (on any pin relative to Ground)	-0.3 to +4.6	V	
V _{IO}	Input or output voltages		-0.3 to V _{CC} to +0.3	V
I _O	Output current	20	mA	
P_{D}	Power dissipation	1	W	

For SO package, Lead-free (Pb-free) lead finish: Reflow at peak temperature of 260°C (total thermal budget not to exceed 245°C for greater than 30 seconds).

Caution: Negative undershoots below –0.3V are not allowed on any pin while in the Battery Back-up mode.

Caution: Do NOT wave solder SOIC to avoid damaging SNAPHAT sockets.

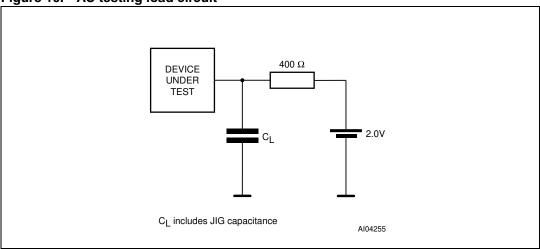
5 DC and AC parameters

This section summarizes the operating and measurement conditions, as well as the DC and AC characteristics of the device. The parameters in the following DC and AC Characteristic tables are derived from tests performed under the Measurement Conditions listed in the relevant tables. Designers should check that the operating conditions in their projects match the measurement conditions when using the quoted parameters.

Table 7. DC and AC measurement conditions

Parameter	M41T315Y	M41T315V/W
V _{CC} supply voltage	4.5 to 5.5V	2.7 to 3.6V
Ambient operating temperature	−40 to +85°C	−40 to +85°C
Load capacitance (C _L)	100pF	50pF
Input rise and fall times	≤5ns	≤5ns
Input pulse voltages	0 to 3V	0 to 3V
Input and output timing ref. voltages	1.5V	1.5V

Figure 10. AC testing load circuit



Note: 50pF for M41T315V.

Table 8. Capacitance

Symbol	Parameter ⁽¹⁾⁽²⁾	Min	Max	Unit
C _{IN}	Input capacitance		10	pF
C _{IO} ⁽³⁾ Input/output capacitance			10	pF

- 1. Effective capacitance measured with power supply at 5V; sampled only; not 100% tested.
- 2. At 25°C, f = 1MHz.
- 3. Outputs were deselected.

Table 9. DC characteristics

			M	41T31	5Y	M417	Γ315V	//W	
Sym	Parameter	Parameter Test condition ⁽¹⁾		-65			-85		
			Min	Тур	Max	Min	Тур	Max	
I _{IL} ⁽²⁾	Input leakage current	$0V \le V_{IN} \le V_{CC}$			±1			±1	μA
I _{OL}	Output leakage current	$0V \le V_{OUT} \le V_{CC}$			±1			±1	μA
I _{CC1} ⁽³⁾	Supply current				10			6	mA
I _{CCO1} ⁽⁴⁾	V _{CC} power supply current	$V_{CC0} = V_{CC1} - 0.3$			150			100	mA
I _{CC2} ⁽³⁾	Supply current (TTL standby)	CEI = V _{IH}			3			2	mA
I _{CC3} ⁽³⁾	V _{CC} power supply current	<u>CEI</u> = V _{CC1} − 0.2			1			1	mA
V _{IL} ⁽⁵⁾	Input low voltage		-0.3		0.8	-0.3		0.6	٧
V _{IH} ⁽⁵⁾	Input high voltage		2.2		V _{CC1} + 0.3	2.0		V _{CC} + 0.3	٧
V _{OL} ⁽⁶⁾	Output low voltage	I _{OL} = 4.0 mA			0.4			0.4	٧
V _{OH} ⁽⁶⁾	Output high voltage	I _{OH} = -1.0 mA	2.4			2.4			٧
V _{PFD}	Power fail deselect		4.25		4.50	2.80 (V) 2.60 (W)		2.97 (V) 2.70 (W)	>
V _{SO}	Battery back-up switchover			V _{BAT}			2.5		٧
V _{BAT}	Battery voltage		2.5		3.7	2.5		3.7	٧
V _{CEO}	CEO output voltage		V _{CC1} - 0.2 or V _{BAT} - 0.2			V _{CC1} – 0.2 or V _{BAT} – 0.2			>
I _{BAT} ⁽³⁾	Battery current	$V_{BAT} = 3.0V$ $T_A = 25^{\circ}C$ $V_{CC} = 0V$			0.5			0.5	μΑ
I _{CCO2} ⁽⁷⁾	Battery backup current	$V_{CC0} = V_{BAT} - 0.2V$			100			100	μA

- 1. Valid for ambient operating temperature: TA = -40 to 85°C; VCC = 4.5 to 5.5V or 2.7 to 3.6V (except where noted).
- 2. Applies to all input pins except \overline{RST} , which is pulled internally to V_{CCI} .
- 3. Measured without RAM connected.
- 4. ICCO1 is the maximum average load current the device can supply to external memory.
- 5. Voltages are referenced to Ground.
- 6. Measured with load shown in Figure 10 on page 19.
- 7. ICCO2 is the maximum average load current that the device can supply to memory in the battery backup mode.

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Table 10.	Crystal electrical characte	eristics (exte	rnally supplied)

Symbol	Parameter ⁽¹⁾⁽²⁾	Min	Тур	Max	Unit
f _O	Resonant frequency		32.768		kHz
R _S	Series resistance			60	kΩ
C _L	Load capacitance		12.5		pF

- These values are externally supplied. STMicroelectronics recommends the KDS DT-38: 1TA/1TC252E127, Tuning Fork Type (thruhole) or the DMX-26S: 1TJS125FH2A212, (SMD) quartz crystal for industrial temperature operations. KDS can be contacted at kouhou@ kdsj.co.jp or http://www.kdsj.co.jp for further information on this crystal type.
- 2. Load capacitors are integrated within the M41T315Y/V/W. Circuit board layout considerations for the 32.768kHz crystal of minimum trace lengths and isolation from RF generating signals should be taken into account.

Figure 11. Power down/up mode AC waveforms

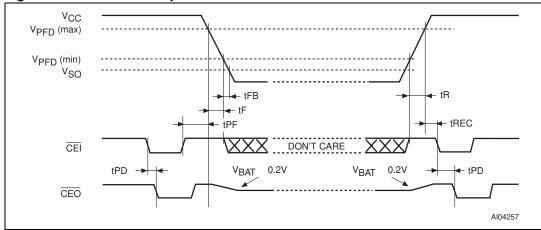


Table 11. Power down/up trip points DC characteristics

Symbol	Parameter ⁽¹	Min	Max	Unit	
t _{REC}	V _{PFD} (max) to CEI low	1.5	2.5	ms	
t _F	V _{PFD} (max) to V _{PFD} (min) V _{CO}	300		μs	
t _{FB}	V _{PFD} (min) to V _{SO} V _{CC} fall time	10		μs	
t _R	V _{PFD} (min) to V _{PFD} (max) V _{CC}	0		μs	
t _{PF}	CEI high to power-fail	0		μs	
t _{PD} ⁽³⁾⁽⁴⁾	CEI propagation delay	M41T315Y		10	ns
	OEI propagation delay	M41T315V/W		15	ns

- Valid for ambient operating temperature: TA = -40 to 85°C; VCC = 4.5 to 5.5V or 2.7 to 3.6V (except where noted).
- 2. Measured at 25°C.
- 3. Measured with load shown in Figure 10 on page 19.
- 4. Input pulse rise and fall times equal 10ns

6 Package mechanical data

In order to meet environmental requirements, ST offers these devices in ECOPACK® packages. These packages have a lead-free second level interconnect. The category of second Level Interconnect is marked on the package and on the inner box label, in compliance with JEDEC Standard JESD97. The maximum ratings related to soldering conditions are also marked on the inner box label. ECOPACK is an ST trademark. ECOPACK specifications are available at: www.st.com.

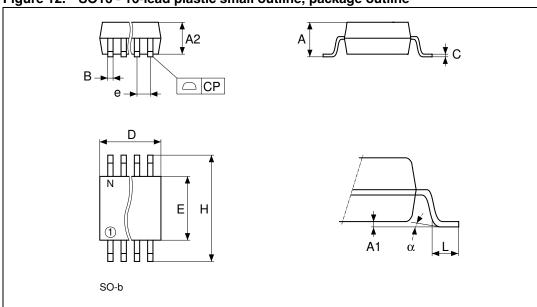


Figure 12. SO16 - 16-lead plastic small outline, package outline

Note: Drawing is not to scale

Table 12. SO16 - 16-lead plastic small outline (150 mils body width), package mechanical data

Cum		mm		inches		
Sym	Тур	Min	Max	Тур	Min	Max
Α			1.75			0.069
A1		0.10	0.25		0.004	0.010
A2			1.60			0.063
В		0.35	0.46		0.014	0.018
С		0.19	0.25		0.007	0.010
D		9.80	10.00		0.386	0.394
E		3.30	4.00		0.150	0.158
е	1.27	-	-	0.050	-	-
Н		5.80	6.20		0.228	0.244
L		0.40	1.27		0.016	0.050
а		0°	8°		0°	8°
N		16			16	
CP			0.10			0.004

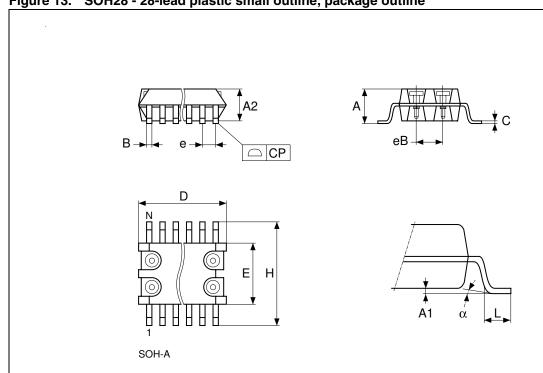


Figure 13. SOH28 - 28-lead plastic small outline, package outline

Note: Drawing is not to scale.

Table 13. SOH28 - 28-lead plastic small outline, package mechanical data

Sym		mm	inches		inches	
Sylli	Тур	Min	Max	Тур	Min	Max
Α			3.05			0.120
A1		0.05	0.36		0.002	0.014
A2		2.34	2.69		0.092	0.106
В		0.36	0.51		0.014	0.020
С		0.15	0.32		0.006	0.12
D		17.71	18.49		0.697	0.728
E		8.23	8.89		0.324	0.350
е	1.27	-	-	0.050	-	-
eB		3.20	3.61		0.126	0.142
Н		11.51	12.70		0.453	0.500
L		0.41	1.27		0.016	0.050
а		0°	8°		0°	8°
N	28				28	
СР			0.10			0.004

A1 A A3 A2

eA B E SHTK-A

Figure 14. SH - 4-pin SNAPHAT housing for 48mAh battery and crystal, package mechanical data

Table 14. SH - 4-pin SNAPHAT housing for 48mAh battery and crystal, package mechanical data

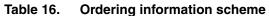
Sum		mm	inches			
Sym	Тур	Min	Max	Тур	Min	Max
Α			9.78		0	0.385
A1		6.73	7.24		0.265	0.285
A2		6.48	6.99		0.255	0.275
А3			0.38		0	0.015
В		0.46	0.56		0.018	0.022
D		21.21	21.84		0.835	0.860
Е		14.22	14.99		0.560	0.590
eA		15.55	15.95		0.612	0.628
eB		3.20	3.61		0.126	0.142
L		2.03	2.29		0.080	0.090

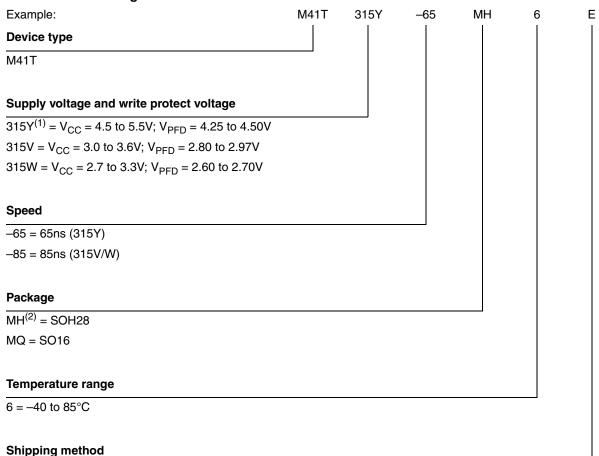
Figure 15. SH - 4-pin SNAPHAT housing for 120mAh battery and crystal, package outline

Table 15. SH - 4-pin SNAPHAT housing for 120mAh battery and crystal, package mechanical data

C		mm				
Sym	Тур	Min	Max	Тур	Min	Max
Α			10.54		0	0.415
A1		8.00	8.51		0.315	0.335
A2		7.24	8.00		0.285	0.315
А3			0.38		0	0.015
В		0.46	0.56		0.018	0.022
D		21.21	21.84		0.835	0.860
Е		17.27	18.03		0.680	0.710
eA		15.55	15.95		0.612	0.628
eB		3.20	3.61		0.126	0.142
L		2.03	2.29		0.080	0.090

7 Part numbering





For SOH28:

blank = Tubes (not for new design - use E)

E = Lead-free package (ECOPACK®), tubes

F = Lead-free package (ECOPACK®), tape & reel

TR = Tape & reel (not for new design - use F)

For SOH16:

blank = Tubes (not for new design - use E)

E = Lead-free package (ECOPACK®), tubes

F = Lead-free package (ECOPACK®), tape & reel

TR = Tape & reel (not for new design - use F)

- 1. Contact local sales office
- The SOIC package (SOH28) requires the SNAPHAT® battery package which is ordered separately under the part number "M4Txx-BR12SHX" in plastic tube or "M4TXX-BR12SHXTR" in tape & reel form (see *Table 17 on page 28*).

Caution:

Do not place the SNAPHAT battery package "M4TXX-BR12SH" in conductive foam as it will drain the lithium button-cell battery.

For other options, or for more information on any aspect of this device, please contact the ST sales office nearest you.

Table 17. SNAPHAT battery table

Part number	Description	Package
M48T28-BR12SH	Lithium battery (48mAh) SNAPHAT	SH
M48T32-BR12SH	Lithium battery (120mAh) SNAPHAT	SH

8 Revision history

Table 18. Document revision history

Date	Revision	Changes
Jun-2001	1.0	First issue
17-Jul-2001	1.1	Basic formatting changes
18-Sep-2001	1.2	Changed pin 8 in 28-pin to V _{SS}
27-Sep-2001	1.3	Added ambient temp to DC characteristics table (Table 9)
01-May-2002	1.4	Modify reflow time and temperature footnote (Table 6)
04-Nov-2002	1.5	Modify crystal electrical characteristics table footnotes (<i>Table 10</i>); add marketing status (<i>Table 16</i>)
26-Mar-2003	1.6	Update test condition (Table 9)
08-Jun-2004	2.0	Reformatted; add lead-free information
26-Nov-2007	3	Reformatted document; product status Not for New Design; added lead-free second level interconnect information to cover page and Section 6: Package mechanical data; updated Table 6.

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